

Application/Control No.	Applicant(s)/Patent under Reexamination
10/685,807	HIROSHIMA ET AL.
Examiner	Art Unit
John B. Nauven	2810

SEARCHED					
Class	Subclass	Date	Examiner		
333	134,202	7/7/2005	NL		
	206,222				
333	208,135	7/7/2005	JN		
			-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		<u>-</u>		
	·			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
text search updated	7/7/2005	JN		
		_		